

Resource Summary Report

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Oxford: Symmetry Electron Microscopy

RRID:SCR_020390

Type: Tool

Proper Citation

Oxford: Symmetry Electron Microscopy (RRID:SCR_020390)

Resource Information

URL: <https://nano.oxinst.com/products/ebsd/symmetry>

Proper Citation: Oxford: Symmetry Electron Microscopy (RRID:SCR_020390)

Description: Symmetry uses customised CMOS sensor to unlock combination of speed, sensitivity and diffraction pattern detail.

Resource Type: instrument resource

Keywords: Oxford, Electron Microscopy, Instrument, Resource equipment, Equipment, USEDit,

Availability: Commercially available

Resource Name: Oxford: Symmetry Electron Microscopy

Resource ID: SCR_020390

Alternate IDs: Model_Number_Symmetry

Record Creation Time: 20220129T080350+0000

Record Last Update: 20260919T195434+0000

Ratings and Alerts

No rating or validation information has been found for Oxford: Symmetry Electron Microscopy.

No alerts have been found for Oxford: Symmetry Electron Microscopy.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.